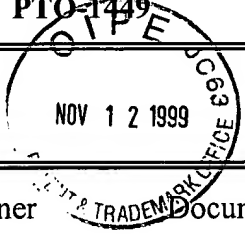


<b>INFORMATION DISCLOSURE STATEMENT</b> PTO-1449	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicants: Yasunori INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit: 2812



### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)	
<u>KB</u>	AA	5,930,624	Murata et al.	7-27-99	438	253	1-26-98
<u>KB</u>	AB	4,962,052	Asayama et al.	10-09-90	437	31	

### FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)	
<u>KB</u>	AC	62-60242	3-16-87	Japan	Abstract
<u>KB</u>	AD	1-199456	8-10-89	Japan	Abstract
<u>KB</u>	AE	3-101130	4-25-91	Japan	Abstract
<u>KB</u>	AF	5-74963	3-26-93	Japan	Abstract
<u>KB</u>	AG	6-349950	12-22-94	Japan	Abstract
<u>KB</u>	AH	2-26055 —	1-29-90	Japan	Abstract
<u>KB</u>	AI	4-234149 —	8-21-92	Japan	Abstract
<u>KB</u>	AJ	7-99195	4-11-95	Japan	Abstract
<u>KB</u>	AK	2-253643	10-12-90	Japan	Abstract
<u>KB</u>	AL	2-7451	1-11-90	Japan	Abstract
<u>KB</u>	AM	8-17770	1-19-96	Japan	Abstract
<u>KB</u>	AN	6-275229	9-30-94	Japan	Abstract
<u>KB</u>	AO	5-198523	8-06-93	Japan	Abstract
<u>KB</u>	AP	4-317358	11-09-92	Japan	Abstract

Examiner	EADN	Date Considered	10/3/00
----------	------	-----------------	---------

RECEIVED  
 NOV 15 1999  
 TECHNOLOGY CENTER 2800



INFORMATION  
DISCLOSURE  
STATEMENT  
PTO-1449

Atty. Docket No. 970150A

Serial No 09/228,148

Applicant(s): INOUE et al.

Filing Date: January 11, 1999

Group Art Unit: 2823

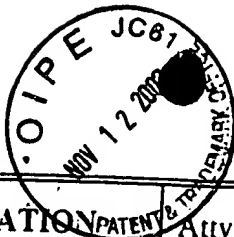
U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<i>Her</i>	AA	5,818,068	Sasaki, et al.	10/98	257	59	09/21/1998
<i>gm</i>	AB	6,001,745	Tu, et al.	12/99	438	78	04/14/1999
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

RECEIVED  
NOV 15 2002  
2800 MAIL ROOM

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
	AK 9-312339	12/21/97	Japan	Abstract
	AL 9-246375	9/19/97	Japan	Abstract
	AM EP 0 602 607 A1	6/22/94	Europe	Yes
	AN 0179563	11/27/98	Korea	Abstract
	AO			
	AP			
	AQ			



INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No. 970150A	Serial No 09/228,148
	Applicant(s): INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit: 2823

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<i>gem</i>	AA	5,818,068	Sasaki, et al.	10/98	257 59	09/21/1998
<i>gem</i>	AB	6,001,745	Tu, et al.	12/99	438 782	04/14/1999
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					

RECEIVED  
NOV 15 2002  
2800 MAIL ROOM

### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
AK	9-312339	12/21/97	Japan
AL	9-246375	9/19/97	Japan
AM	EP 0 602 607 A1	6/22/94	Europe
AN	0179563	11/27/98	Korea
AO			
AP			
AQ			

<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicant(s): Yasunori INOUE	
	Filing Date: January 11, 1999	Group Art Unit: 2814

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>KE</u>	AA	5,341,026	Harada et al.	8/23/94	257	758
<u>KE</u>	AB	5,373,192	Eguchi	12/13/94	257	758
<u>KE</u>	AC	5,523,616	Den	6/04/96	257	758
<u>KE</u>	AD	5,519,254	Tabara	5/21/96	257	758
<u>KE</u>	AE	5,387,812	Forouhi et al.	2/07/95	257	758
<u>KE</u>	AF	5,310,700	Lien et al.	5/10/94	257	758

### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
<u>KE</u> AG 2-235358	09/18/90	JAPAN	Partial
<u>KE</u> AH 5-226334	09/03/93	JAPAN	Partial
AI			
AJ			
AK			

### OTHER DOCUMENTS

<u>KE</u>	AL	Sze, <u>Physics of Semiconductor Devices</u> , 2nd Ed. 1981, p. 393.
	AM	
Examiner <u>KEH EATON</u>		Date Considered <u>10/3/00</u>

<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicant(s): Yasunori INOUE	
	Filing Date: January 11, 1999	Group Art Unit: 2814

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
KB	AA 4,668,973	Dawson et al.	5/26/87	257	634	
KB	AB 4,676,867	Elkins et al.	6/30/87	257	752	
	AC					
	AD					
	AE					
	AF					

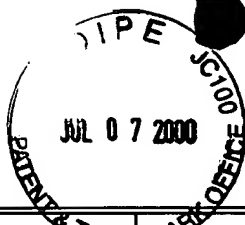
### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
AG			
AH			
AI			
AJ			
AK			

### OTHER DOCUMENTS

AL	
AM	

Examiner	Kurt EATON	Date Considered	10/3/80
----------	------------	-----------------	---------



**INFORMATION  
DISCLOSURE  
CITATION  
PTO-1449**

Atty. Docket No. 970150A

Serial No. 09/228,148

Applicant(s): Y. INOUE et al.

Filing Date: January 11, 1999

Group Art Unit: 2812

**OTHER DOCUMENTS**

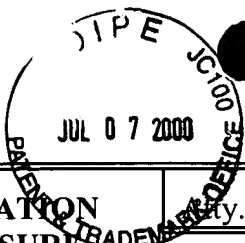
	<del>AY</del>	<del>Wang et al., "A Study of Plasma Treatments on Siloxane SOB," IEEE VMIC Conference, June 7-8, 1994, pp. 101-107</del>
	<del>AZ</del>	<del>Chiang et al., "Defects Study on Spin on Glass Planarization Technology, IEEE VMIC Conference, June 15-16, 1987, pp. 404-412.</del>
	<del>BA</del>	<del>Lai Juh Chen, et al., "Fluorine Implanted Treatment (FIT) SOG for the Non Etchback Intermetal Dielectric," IEEE VMIC Conference, June 7-8, 1994, pp. 81-86.</del>
<i>VB</i>	<del>BB</del>	<del>Moriya et al., "Modification Effects in Ion-Implanted SiO<sub>2</sub> Spin on Glass," J. Electrochem. Soc., Vol. 140, No. 5, May 1993, pp. 1442-1450.</del> <i>disregard mark</i>
	<del>BC</del>	<del>Matsuura et al., "An Advanced Interlayer Dielectric System with Partially Converted Organic SOG Using Plasma Treatment," IEEE VMIC Conference, June 8-9, 1993, pp. 113-115.</del>
<i>VB</i>	BD	Ishida et al., "Mechanism for ALSiCu alloy Corrosion," <u>Jpn. J. Appl. Phys.</u> , Vol. 31 (1992), pp. 2045-2048.
	<del>DE</del>	<del>Doki et al., "Moisture-Blocking Mechanism of ECR Plasma," IEEE VMIC Conference, June 7-8, 1994, pp. 235-239.</del>
	<del>DF</del>	<del>Shimokawa et al., "Suppression of MOSFET hot carrier degradation by P-SiO underlayer," The Institute of Electronics, Information and Communication Engineers, Technical Report of IEICE, SDM92-133 (1992-12), pp. 89-94.</del>
<i>VB</i>	BG	Murase et al., "Dielectric Constant of Silicon Dioxide Deposited by Atmospheric-Pressure Chemical Vapor Deposition Using Tetraethylorthosilicate and Ozone," <u>Jpn. J. Appl. Phys.</u> , Vol. 33 (1994), pp. 1385-1389.

Examiner

Date Considered

Kurt Eaton

12/3/00



<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Patent No. Docket No. 970150A	Serial No. 09/228,148
	Applicant(s): Y. INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit: 2812

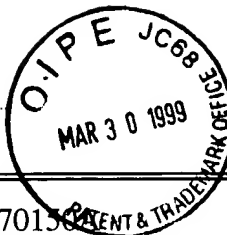
### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>VB</u>	AA	6,013,578 Jun	01/2000	438	687	
<u>VB</u>	AB	5,963,827 Enomoto et al.	10/1999	438	629	
<u>VB</u>	AC	5,786,273 Hibi et al.	07/1998	438	637	
<u>VB</u>	AD	5,153,680 Naito et al.	10/1992	357	8	
<u>VB</u>	AE	3,747,203 Shannon	07/1973	29	578	
<u>VB</u>	AF	5,166,768 Ito	11/1992	257	523	
<u>VB</u>	AG	4,775,550 Chu et al.	10/1988	427	38	
<u>VB</u>	AH	4,885,262 Ting et al.	12/1989	437	231	
<u>VB</u>	AI	4,983,546 Hyun et al.	01/1991	437	231	
<u>VB</u>	AJ	5,003,062 Yen	03/1991	437	231	
<u>VB</u>	AK	5,106,787 Yen	04/1992	437	231	
<u>VB</u>	AL	5,352,630 Kim et al.	10/1994	437	195	
<u>VB</u>	AM	5,549,786 Jones et al.	08/1996	156	662.1	
<u>VB</u>	AN	4,984,055 Okumura et al.	01/1991	257	644	
<u>VB</u>	AO	5,270,259 Itoh et al. —	12/1993	437	235	
<u>VB</u>	AP	5,468,684 Yoshimori et al.	11/1995	437	228	
	AQ					

### FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
<u>VB</u>	AR 4,218,495 A1	12/10/92	Germany	
<u>VB</u>	AS 1-307247	12/12/89	Japan	
<u>VB</u>	AT 5-226334	03/09/93	Japan	
<u>VB</u>	AU 2-101532 —	08/13/90	Japan	
<u>VB</u>	AV 2-235358 —	09/18/90	Japan	
<u>VB</u>	AW 4-307934 (A)	10/30/92	Japan	
<u>VB</u>	AX 8-64561	3/8/96	Japan	

NO  
ABSTRACT



<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Atty. Docket No. 970156	Serial No. 09/228,148
	Applicant(s): INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit:

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>VB</u>	AA	5,607,880	SUZUKI et al.	3/04/97	437	195
<u>VB</u>	AB	5,429,990	LIU et al.	7/04/95	437	190
<u>VB</u>	AC	5,192,697	LEONG	3/09/93	437	37
_____	AD					
_____	AE					

### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
_____	AF		
_____	AG		
_____	AH		
_____	AI		
_____	AJ		

**RECEIVED**  
APR 01 1999  
TECHNOLOGY CENTER 2800

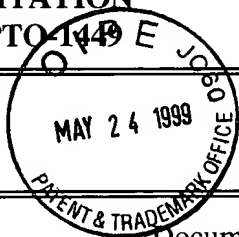
### OTHER DOCUMENTS

_____	AK	
_____	AL	
Examiner	<u>Kurt Eaton</u>	Date Considered <u>12/3/00</u>



45

INFORMATION DISCLOSURE CITATION PTO-1449 E	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicant(s): INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit:



### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>KB</u>	AA	5,753,975	Matsuno	5/19/98	257	751
<u>KB</u>	AB	5,702,568	Shin et al.	12/30/97	156	644.1
<u>KB</u>	AC	5,665,845	Allman	9/09/97	528	5
<u>KB</u>	AD	5,514,910	Koyama	5/07/96	257	768
<u>KB</u>	AE	5,479,054	Tottori	12/26/95	257	752
<u>KB</u>	AF	5,087,589	Chapman et al.	2/11/92	437	195
<u>KB</u>	AG	5,084,412	Nakasaki	1/28/92	437	189

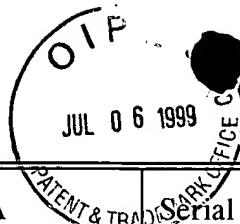
### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
_____ _____ _____	AH AI AJ	<b>RECEIVED</b> MAY 27 1999	
_____			
_____			
_____			

TECHNOLOGY CENTER 2800

### OTHER DOCUMENTS

_____ _____	AK AL	
_____		
Examiner	Date Considered	
<u>Kurt Eaton</u>	<u>12/3/00</u>	



<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Atty. Docket No. 970150A		Serial No. 09/228,148
	Applicant(s): INOUE et al.		
	Filing Date: January 11, 1999		Group Art Unit: 2812

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>16</u>	AA	5,866,476	Choi et al.	2/02/99		
<u>16</u>	AB	5,855,962	Cote et al.	2/05/99		
<u>16</u>	AC	5,817,582	Maniar	10/06/98		
<u>16</u>	AD	5,569,618	Matsubara	10/29/96		
<u>16</u>	AE	5,496,776	Chien et al.	3/05/96		
<u>16</u>	AF	5,192,697	Leong	3/09/93		
<u>16</u>	AG	5,186,745	Maniar	2/16/93		
	AH					

RECEIVED  
TECHNOLOGY CENTER 2800

### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
<u>16</u> AI 9-104698	11/13/98	Japan	Abstract only
<u>16</u> AJ 9-58062	3/12/97	Japan	No
<u>16</u> AK 9-8949	1/21/97	Japan	No
<u>16</u> AL 8-241891	9/17/96	Japan	No

### OTHER DOCUMENTS

<u>16</u>	AM	Japanese Patent Laying-Open 59-017243 (abstract).
<u>16</u>	AN	Japanese Patent Laying-Open No. 58-031519 (abstract).
Examiner <u>Kurt EADN</u>		Date Considered <u>12/3/00</u>